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# **SPARSE: a high performance** scatterometer with imaging ability

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## **OBJECTIVES**

- Measure maps of Bidirectional Scattering Distribution Functions (BSDF).
- Discriminate and quantify the light scattered by intrinsic roughness from that of defects and contaminants.

## **KEY PRINCIPLES OF SPARSE**

- Reciprocity (scanning the illumination angle).
- Telecentric imager (bijection between CCD pixel and surface element).
- High Dynamic Range.

# **SPECIFICATIONS**

2.6

Performing, on 25 mm diameter sample, up to 400 000 BSDF patterns

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# SPARSE INSTRUMENT

# **SPAtially and Angularly Resolved Scatterometry Equipment**



- measurement simultaneously.
- > Air diffraction limited: ARS at  $10^{-8}sr^{-1}$
- Having an agile selection of the area to be analyzed.

## PROBLEMATIC





Because defects and contaminants have an impact on scattering losses that is hard to quantify with a classical scatterometer, we developped a scatterometer with imaging capabilities: SPARSE. The instrument couples the principles of a scatterometer with an imaging system to spatially resoled BRDF and transmission signals. It can resolve, on a one inch diameter component, up to around 400 000 microsurfaces of 26x26µm and record the corresponding 400 000 BSDF paterns for each.

# **BRDF MEASUREMENT OF A SILVER COATED MIRROR**

 $10^{-1}$ 

**Total Integrated Scattering(TIS) map log plot** 



**ARS** measured on the sample R a

Signal to Noise Ratio map at 45°



## **MAPPING OF THE LOCAL TRANSMISSION - APPLICATION TO A NEUTRAL DENSITY**



# **NEXT MILESTONES**

- Transfert SPARSE in a clean room to work under a controlled environment.
- Extend the metrology of scattered light to BTDF.
- Measurement at multiple wavelengths.
- Develop AI classification software coupled with electromagnetic models to extract structural information on defects and contamination

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SPARSE is part of the DIFFUSIF platform (*fresnel.fr/diffusif*) as scattered light metrology instrument.

